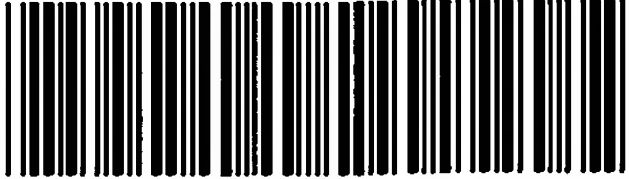


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/660,585	AIZAWA, TAKASHI	
	Examiner	Art Unit	
	Tuan H. Le	2622	

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Class	Subclass	Date	Examiner
348	211	12/7/2006	TL
348	231.1-3,6	12/7/2006	TL
348	231.6,9	12/7/2006	TL
348	207.99,1	12/7/2006	TL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor name search	12/6/2006	TL
US-PGPUB,USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB	12/6/2006	TL